

Resource Summary Report

Generated by [PRECISE-TBI](#) on Jul 31, 2026

FEI: ExSolve Wafer TEM Prep DualBeam

RRID:SCR_019882

Type: Tool

Proper Citation

FEI: ExSolve Wafer TEM Prep DualBeam (RRID:SCR_019882)

Resource Information

URL: <https://www.fei.com/products/dualbeam/exsolve/>

Proper Citation: FEI: ExSolve Wafer TEM Prep DualBeam (RRID:SCR_019882)

Description: Sample preparation workflow that is used for transmission electron microscopy (TEM) analysis.

Resource Type: instrument resource

Keywords: FEI, sample preparation system, Instrument, Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: ExSolve Wafer TEM Prep DualBeam

Resource ID: SCR_019882

Alternate IDs: Model_Number_ExSolve Wafer

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260725T190920+0000

Ratings and Alerts

No rating or validation information has been found for FEI: ExSolve Wafer TEM Prep DualBeam.

No alerts have been found for FEI: ExSolve Wafer TEM Prep DualBeam.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.